


Search Notes 	Application/Control No. 10551671	Applicant(s)/Patent Under Reexamination ADAMEK ET AL.
	Examiner SHEELA C CHAWAN	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103, 177, 215, 154, 165, 100, 164, 282, 154, 151, 174, 177, 203, 238, 291, 289, 174, 242, 241, 199,	11/9/08	SCC
714	701	"	"
345	419, 468, 441, 471, E13.005, E13.014, E13.015, E13.016, E13.018, E13.019, E13.025, E13.061, E13.062, E13.071	"	"
375	E7.081	"	"
295	21, 44, 11, 15	"	"
250	559.23	"	"
700	187	"	"
382	151, 203, 219	6/20/09	SCC
345	441	6/20/09	SCC
ABOVE SEARCH-UPDATE		6/20/09	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	11/9/08	SCC
SEARCH INVENTOR NAME	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY	6/20/09	SCC
382/103, 177, 215, 154, 165, 100, 164, 282, 154, 151, 174, 177, 203, 238, 291, 289, 174, 242, 241, 199" CCLS. US-PATENT TEXT SEARCH ONLY.	6/20/09	SCC
345/419, 468, 441, E13.005, E13.014, E13.015, E13.016. CCLS. TEXT SEARCH ONLY.	6/20/09	SCC
714/701. CCLS. TEXT SEARCH ONLY.	6/20/09	SCC
700/187. CCLS. " "	6/20/09	SCC
INTERFERENCE SEARCH.	6/20/09	SCC
345/E7.081 ABOLISH	6/20/09	SCC
SEARCH IEEE OR INSPEC DATA BASE.	6/20/09	SCC
SEARCH UP-DATE.	6/20/09	SCC

INTERFERENCE SEARCH

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Class	Subclass	Date	Examiner
382	151,203,219	6/20/09	SCC
345	441	6/20/09	SCC

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